INDUSTRIAL INSPECTION MICROSCOPE



Your Vision, Our Future







## The best way to the best results





The MX51 Effect: More Efficient Inspections Throughout Industry.





## Streamlined operation for faster, more comprehensive results

#### Agile stage movement and coarse/fine movement interchange.

Two stage sizes are available, 150mm and 100mm. The 150mm stage has a built-in clutch lever, which enables quick location of specimens on the stage without diverting the operator's view, allowing quick, easy inspections.

## Repositioned optical controls for smoother performance.

Controls for focusing and light intensity adjustment are placed closer together, so that both can be operated with one and the same hand.

## Anti-static treatment prevents dust contaminating the sample.

The frame and 6-inch stage are coated to prevent static build-up.

\* Use special metal plate.

## SEMI S2/S8 compliance enhances safety and ergonomics.

The convenience of front operation is one of the Olympus' key design concepts, complemented by compliance with international industry standards to guarantee superior reliability.

## Motorized revolving nosepiece enables direct exchange of objectives for higher efficiency.

In addition to the standard nosepiece, the MX51 can be equipped with a range of motorized nosepieces. An external handset allows direct selection of the desired objective. The MX51 also offers a centerable, motorized nosepiece for accurate

positioning for easy observation at high magnifications.



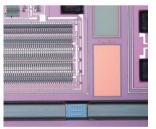


# Practical versatility: the MX51 is ideal for many different kinds of inspections

#### Latest UIS optics maximize detection of even tiny defects.

Fast, accurate detection of defects, and hence fewer check failures, are ensured by the MX51's enhanced brightfield/darkfield observation capabilities, which deliver approximately 4\* times greater detection sensitivity than previous model. Outstanding accuracy in observation of small diameter wafers

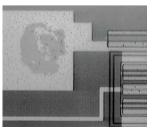
such as those used in today's smaller sensors and many other highperformance electronic devices. \*In the recommended set of objective lens.



#### Offers multiple observation methods from visible to fluorescence and near-IR.

The standard illuminator (BX-RLA2) complies with near IR observation, as well as offering brightfield, darkfield, Nomarski DIC and simple polarizing

observations. A universal illuminator (BX-URA2) is also available for fluorescence observation.



#### Transmitted light observation.

The combination of a transmitted illumination unit with the 150mm stage enables transmitted light brightfield observation of samples up to 2mm thick, with an illumination range of 100X100mm. The slimprofiled illumination unit is designed for minimal effect on the stage operation and is useful for observations of samples such as MEMS (Micro Electronics Mechanical Systems) sensors and other

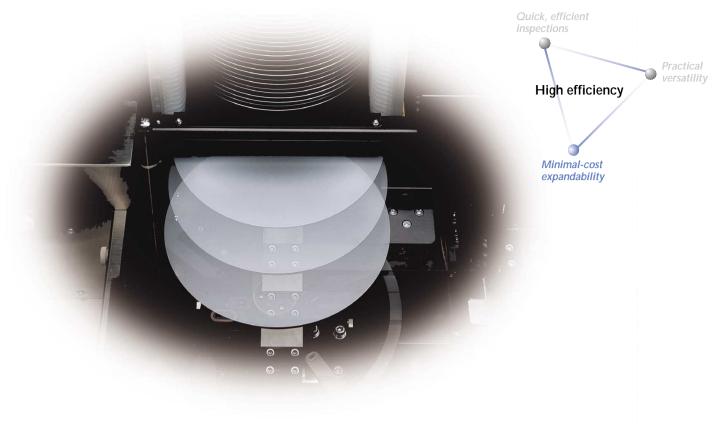
optical/optronic components.



#### Intermediate attachment raises objectives to accommodate thick samples.

The standard maximum sample thickness is 30mm. Insert the intermediate attachment to accommodate thicker samples.





#### Expandability:

## adding extra functions at minimal cost

#### Combine with wafers loaders to increase work efficiency.

Use of the AL110-6 series wafer loaders, which accept wafers up to 150mm, offers front- and backmacro inspection and microscope inspection without the operator handling the wafers.



#### Confocal module for high-resolution, high-contrast observations.

The confocal module (U-CFU) employs an original disk scanning method to deliver high-contrast, high-

resolution observation images. This allows inspection of multi-layered electronic devices.



## Digital imaging with excellent cost performance.

A wide range of cost-effective Olympus digital cameras can be added to the MX51. Additionally,

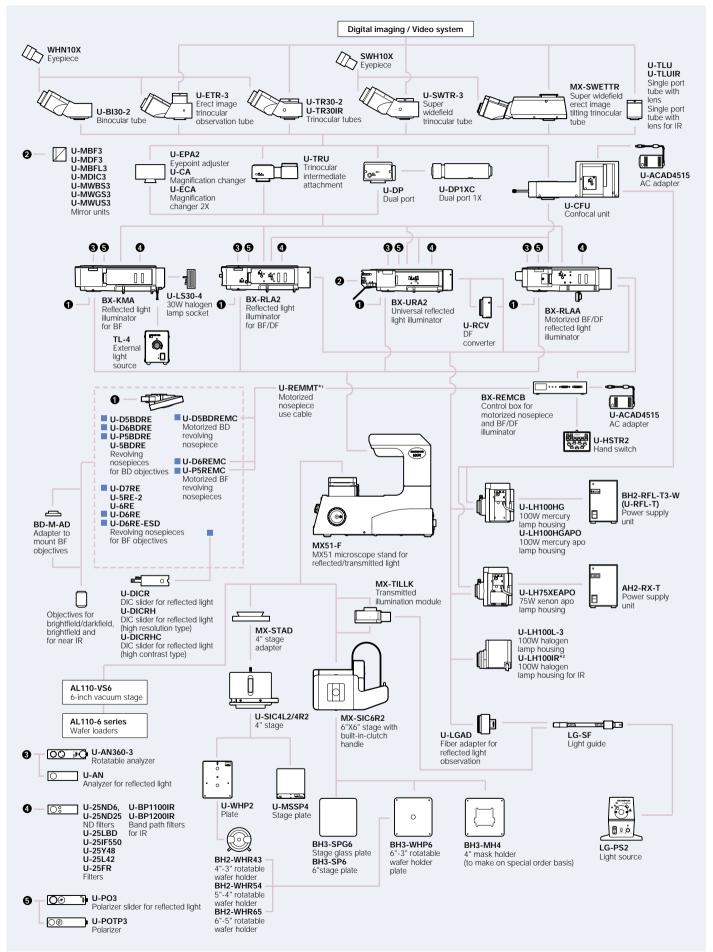
adapters allow the use of digital or video cameras currently in use.



DP12 configuration

Accepts many high-quality BX2M accessories. A wide range of the highly-regarded BX2M series accessories can be used, including a tilting observation tube, motorized illuminator, various lamp housings, motorized revolving nosepieces, mirror units, prisms, filters and intermediate attachments.

System Diagram

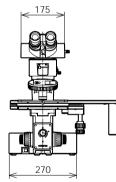


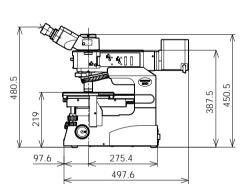
#### ■ Specifications

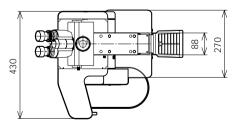
Optics		UIS Optics (infinity-corrected system)					
Microscope stand		2-guide rack and pinion method Coarse and fine co-axial Z-axis control stroke 32mm (2mm upper and 30mm below from the focal plane) The same stroke 15mm (combination with transmitted illumination) Stroke per rotation of fine Z-axis control 0.1 mm (1 unit 1μm) Coarse handle torque adjustment Coarse handle upper limit lever					
Illumination		BX-KMA Brightfield illuminatior	BX-RLA2 Brightfield/Darkfield illuminator		BX-URA2 Universal Fluoresccence illuminator		
	Contrast changeover method	_	BF-DF slide method		Mirror (Max. up to 6) turret motheod		
	Applicable observation mode	(1) Brightfield (2) Normaski DIC (3) Polarized light	1 Brightfield 2 Darkfield 3 Normaski DIC 4 Polarized light ⑤ IR		(1) Brightfield (2) Darkfield (3) Normaski DIC (4) Polarized light (5) Fluorescence		
Lamphousing		6V30W Halogen Lamp socket: U-LS30-4 Transformer: TL-4	12V100W Halogen Lamphouse: U-LH100L-3 Power supply is integrated in MX51		Mercury lamp house: U-LH100HGAPO External power supply BH2-RFL-T3 needed		
Transmitted illumination		Brightfield MX-TILLK combined with fiber light guide illumination (configured with MX-SIC6R2)					
Power supply unit		_			0-240V~1.8A/0.8A 50/60Hz ht intensity dial		
Observation tube		U-BI30-2 Widefield binocular, U-TR30-2 Widefield trinocular, U-ETR3 Widefield erect image trinocular (F.N. 22) U-SWTR Superwidefield trinocular, MX-SWETTR Superwidefield erect image tilting trinocular (F.N. 26.5)					
Revolving nosepiece		U-5RE-2, U-6RE U-D5BDRE, U-D6BDRE, U-P5BDRE (with slider slot for DIC Prism)					
Stage		U-SIC4R2/SIC4L2 Coaxial right/left-hand control 4"X4" stage		MX-SIC6R2 Coaxial right/left-hand control 6"X6" stage			
		Drive method: rack and pinion method Y axis stopper: lever method		Drive method: Belt method Stroke: 158(X) X158 (Y) mm Clutch method: 2 clutch plates (Built-in-clutch ON/OFF handle) Holder dimensions: 200 X 200mm Transmitted light area: 100 X 100mm			
Dimensions & Weight		Dimensions: Approx. 430(W) X 591(D) X 495(H)mm Weight: Approx. 26kg (Stand Approx. 11kg)					

#### Dimensions (unit: mm)

#### MX51

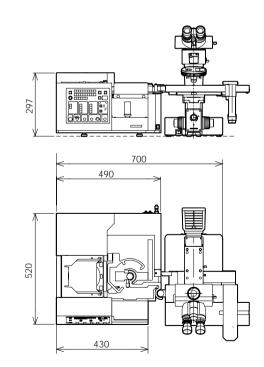






#### MX51+AL110-6

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#### ■Objectives

Lens Optical character	Magnifi- cation	N.A.	W.D. (mm)	Cover glass thickness (mm)	Resolu- tion <sup>*2</sup> (μm)				
UMPLFL	5X 10X 20X 40X 50X 100X	0.15 0.30 0.46 0.75 0.80 0.95	20.0 10.1 3.1 0.63 0.66 0.31		2.24 1.12 0.73 0.45 0.42 0.35				
UMPLFL-BD	5X 10X 20X 50X 100X	0.15 0.30 0.46 0.80 0.90	12.0 6.5 3.0 0.66 0.31		2.24 1.12 0.73 0.42 0.37				
UMPLFL-BDP	5X 10X 20X 50X 100X	0.15 0.25 0.40 0.75 0.90	12.0 6.5 3.0 0.66 0.31	 0 0 0	2.24 1.34 0.84 0.45 0.37				
LMPLAPO	150X 250X	0.9 0.9	1.0 0.80	0 0	0.37 0.37				
LMPLAPO-BD	150X 250X	0.9 0.9	1.0 0.80	0 0	0.37 0.37				
LMPLFL	5X 10X 20X 50X 100X	0.13 0.25 0.40 0.50 0.80	22.5 21.0 12.0 10.6 3.4	 0 0 0	2.58 1.34 0.84 0.67 0.42				
LMPLFL-BD	5X 10X 20X 50X 100X	0.13 0.25 0.40 0.50 0.80	15.0 10.0 12.0 10.6 3.3	 0 0 0	2.58 1.34 0.84 0.67 0.42				
MPLAPO	20X 50X 100X 100XOil	0.60 0.95 0.95 1.40	0.90 0.30 0.35 0.1	0 0 0 0	0.56 0.35 0.35 0.24				
MPLAPO-BD	100X	0.9	0.31	0	0.37				
MPLFL-BD	50X 100X	0.8 0.9	1.0 1.0	_	0.42 0.37				
MPL*3	5X 10X 20X 50X 100X	0.10 0.25 0.40 0.75 0.90	19.6 10.6 1.3 0.38 0.21	 0 0 0	3.36 1.34 0.84 0.45 0.37				
MPL-BD*1*3	5X 10X 20X 50X 100X	0.10 0.25 0.40 0.75 0.90	12.0 7.0 1.3 0.38 0.21		3.36 1.34 0.84 0.45 0.37				
SLMPL	20X 50X	0.35 0.45	21.0 15.0	0 0	0.58 0.75				
LCPLAPO	20X 50X	0.40 0.60	8.8 3.1	0/0.7/1.1 0/0.7/1.1	0.84 0.56				
LCPLFL-LCD	100X	0.80	0.95/ 1.1/ 1.143	0.6-1.2	0.42				
LMPL-IR	5XIR 10XIR 20XIR 50XIR 100XIR	0.10 0.25 0.40 0.55 0.80	20.0 18.5 8.1 6.0 3.4	 	 				
MPL-IR	100XIR	0.95	0.3	_	_				

\*1 When MPL-BD objectives are used in combination with the U-LH100HGAPO/ULH75XEAPO lamp housing (mercury/xenon socket) for darkfield observation, illumination near the perimeter of the field of view may be slightly insufficient depending on the specimen. \*2 Resolving power calculated with the aperture diaphragm fully opened. \*3 Up to F.N. 22.

•OLYMPUS CORPORATION obtains ISO9001/ISO14001.

Specifications are subject to change without any obligation on the part of the manufacturer.



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